

FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTORNEY DOCKET NO. 2077.D1/SILICON/MBE			09/595,278 SERIAL NO. 4474						
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: Grimbergen, et al.			FILING DATE: Herewith GROUP: Unknown 1796						
					FILING DATE: Herewith									
U.S. PATENT DOCUMENTS														
Examiner Initial	A1*	4	1	9	8	2	6	1	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<div style="font-size: 2em; font-weight: bold;">A10</div>	A1*	4	1	9	8	2	6	1	4/15/80	Busta, et al.	156	626	<div style="writing-mode: vertical-rl; transform: rotate(180deg);"> J-288 U.S. PTO 09/595578 09/16/02 </div>	
	A2*	4	2	0	8	2	4	0	6/17/80	Latos	156	627		
	A3*	4	4	9	3	7	4	5	1/15/85	Chen, et al.	156	626		
	A4*	4	8	4	2	6	8	3	6/27/89	Cheng, et al.	156	345		
	A5*	4	8	5	9	2	7	7	8/22/89	Barna, et al.	156	626		
	A6*	4	9	5	3	9	8	2	09/1998	Ebbing, et al.	356	357		
	A7*	4	9	7	5	1	4	1	12/04/90	Greco, et al.	156	626		
	A8*	5	0	0	2	6	3	1	03/26/91	Giapis, et al.	156	643		
	A9*	5	2	0	0	0	2	3	4/6/93	Gifford, et al.	156	626		
	A10*	5	3	6	2	3	5	6	11/8/94	Schoenborn	156	626		
	A11*	5	3	7	2	6	7	3	12/1994	Stager, et al.	438	008		
	A12*	5	3	7	2	6	7	3	12/1994	Stager, et al.				DUPLICATE
	A13*	5	3	9	2	1	2	4	2/21/95	Barbee, et al.	356	281		
	A14*	5	3	9	9	2	2	9	3/21/95	Stefani, et al.	156	626		
	A15*	5	4	0	3	4	3	3	4/1995	Morrison, et al.	216	060		
	A16*	5	4	0	6	0	8	0	4/11/95	Friedheim	250	309		
	A17*	5	4	4	5	7	0	5	8/29/95	Barbee, et al.	156	627.1		
	A18*	5	4	5	0	2	0	5	9/12/95	Sawin, et al.	356	382		
	A19*	5	4	5	1	2	8	9	9/19/95	Barbee, et al.	216	059		
	A20*	5	4	5	6	7	8	8	10/10/95	Barbee, et al.	156	345		
	A21*	5	4	6	7	8	8	3	11/21/95	Frye, et al.	216	060		
	A22*	5	4	7	2	5	0	8	12/1995	Saxena	118	723EE		
	A23*	5	5	3	6	3	5	9	7/1996	Kawada, et al.	438	016		
	A24	5	6	5	4	9	0	3	8/5/97	Reitman, et al.	364	551.01		
	A25	5	6	9	1	5	4	0	11/25/97	Halle, et al.	250	372		
	A26*	5	7	1	6	4	5	1	2/10/98	Hama, et al.	118	723		
	A27	5	7	4	7	3	8	0	5/5/98	Yu, et al.	438	599		
	A28*	5	7	7	0	0	9	7	6/1998	O'Neill, et al.	216	060		
	A29*	5	7	9	2	2	7	2	8/1998	Van Os, et al.	118	723R		
	A30*	5	8	0	7	7	6	1	09/1998	Coronel, et al.	438	014		
EXAMINER <i>Alt. w. O'Brien</i>										DATE CONSIDERED 4/16/02				
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.														

FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				ATTORNEY DOCKET NO. 2077.D1/SILICON/MBE				09/595,778 SERIAL NO. 44A	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)						APPLICANT: Grimbergen, et al.				FILING DATE: Herewith	
						GROUP: 1776				UNKNOWN	
U.S. PATENT DOCUMENTS											
Examiner Initial	DOCKET NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE					
<i>AW</i>	A31	5 8 3 4 3 7 5	11/10/98	Chen	438 692						
<i>AW</i>	A32*	5 8 4 6 8 8 3	12/8/98	Moslehi	438 711						
	A33										
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EXAMINER <i>Ma. Obe</i>				DATE CONSIDERED <i>4/16/02</i>							
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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTORNEY DOCKET NO. 2077.D1/USA/SILICON/MBE

09/695,773
SERIAL NO. -N/A

LIST OF ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT: Grimbergen, ET AL.

FILING DATE: Herwith

GROUP: unknown 1786

FOREIGN PATENT DOCUMENTS

		DOCKET NUMBER							DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
													YES	NO
Hand	B1*	0	7	3	5	5	6	5	02/10/96	EP APPLICATION				
Hand	B2	0	7	5	6	3	1	8	1/19/97	EP APPLICATION	H01L	21/66		
Hand	B3*	0	7	8	8	1	3	8	08/06/97	EP APPLICATION				
	B4													
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U.S. PTO
09/695,773
06/16/00

EXAMINER

Allen W. Olson

DATE CONSIDERED

7/14/02

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FORM PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTORNEY DOCKET NO. 2007.D1/USA/SILICON/MBE		09/595,778 SERIAL NO. 444	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Grimbergen, et al.		FILING DATE: Herewith	
				GROUP: Unknown		1776	
OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)							
Acw	C1*	International Search Report, dated February 17, 1999					
	C2*	Principles of Instrumental Analysis, 2 nd Ed., Skoog and West (Saunders, 1980) pages 181, 182, 193, 245					
	C3*	Sofie Instruments- Product User's Manual, Digitwin DATE UNKNOWN					
	C4*	""In-Situ Control and Diagnosis of Deposition and Etch Processes is Possible Using Interferometry Combined with CCD Imaging", European Semi-Conductor, March 1995, pages 14-17					
Acw	C5*	F. Heinrich; P. Kopperschmidt, "Online Uniformity Measurements in Large Area Plasma Assisted Etching and Deposition", Proceedings of the 10 th International Colloquium on Plasma Processes CIP '95", Antibes, France, June 11-15 1995					
	C6						
	C7						
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EXAMINER <i>Ala. Ols</i>				DATE CONSIDERED 4/16/02			
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